

<b>Notice of References Cited</b>	Application/Control No. 10/510,245		Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner Alexander Markoff		Art Unit 1792	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0001392	05-2001	Hirae et al.	134/1.3
*	B	US-4,783,006	11-1988	Hayashi et al.	239/380
*	C	US-5,510,158	04-1996	Hiramoto et al.	427/582
*	D	US-5,677,113	10-1997	Suzuki et al.	430/329
*	E	US-5,998,766	12-1999	Mizosaki et al.	219/390
*	F	US-6,610,168	08-2003	Miki et al.	156/344
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003064486 A	03-2003	Japan	NAKATANI, MINORU	
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.